

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/711,424 <b>Examiner</b> D. Rutledge	<b>Applicant(s)/Patent under Reexamination</b> VOLLRATH ET AL.		
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>			
Class	Subclass	Date	Examiner	US Pat/PGPub, Derwent, EPO, JPO; text search; see printout		DATE	EXMR
<b>INTERFERENCE SEARCHED</b>							
Class	Subclass	Date	Examiner				